

Notice of References Cited

Application/Control No.

10/594,842

Applicant(s)/Patent Under
Reexamination
MURAKAWA ET AL.

Examiner

Leigh Marie Garbowski

Art Unit

2825

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,314,390	11-2001	Bittner et al.	703/14
*	B	US-6,637,008	10-2003	Higuchi et al.	716/2
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	COELLO, Carlos A., "An Updated Survey of GA-Based Multiobjective Optimization Techniques," ACM Computing Surveys, Vol. 32, No. 2, June 2000, pages 109-143.
	W	KESER, Milan and JOARDAR, Kuntal, "Genetic Algorithm Based MOSFET Model Parameter Extraction," Technical Proceedings of the 2000 Int'l Conference on Modeling and Simulation of Microsystems, pages 314-344.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.